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Assignment Number

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Nai-Yin Sung et al.

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J. Dreibelbis, et al., "Processor-Based Built-In Self-Test for Embedded DRAM", IEEE Journal of Solid-State Circuits, Vol. 33, No. 11, Nov. 1998, pp. 1731-1740.

"Built-In Self-Test (BIST) Using Boundary Scan", Texas Instruments Corp., Dec. 1996, pp. 1-8.

I. Burgess, "Test and Diagnosis of Embedded Memory Using BIST,"
Mentor Graphics Corp., Sept. 2000, pp. 1-6.

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